A Complete Bibliography of Publications in *Technometrics* for the decade 1990–1999

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Dea96, Dea97, Deh90, Der90, Dic91, Dic97, Die92, Dob96, Dog93, Dog99, Dom90, Don90, Dov93, Dow95, Dre91, Dri91, Dri92, Dun90, Dun96, Dun97, Eas90, Eas99, Edg92, Edg98, Elt90, Emp92, Emp93, Emp97, Emp99, Ens95, Eub90, Eub93, Fai91, Fai94, Fal99, Fam95, Fam97, Fam99, Far90]. **Book** [Far92, Far93, Fot95, Fot96, Fox91, Fox94, Fox97, Fox98, Fre92, Fre99, Fre93, Fre94, Fre95, Fre97, Fri97, Ful95, Ful97, Gal95, Gal92, Gal93, Gan97, Gas97, Gas94, Gat96, GR97, Geo94, Geo98, Gho93, Gho94, Gib91, Gil92, Gla98, Gle91, Gle96, Glo93, Glo95, Glo97, Glo99, God93, God95, Goi96, Gol99, Gol95, Gol93, Gol98, Gol90, Goo91, Goo92a, Goo95, Goo92b, Got92, Got94a, Gov92, Gra90, Gra94, Gra98, Gre94, Gre98, Gri90, Gri96, Gri97a, Gri99, Gri98, Gri95, Gro92, Gro96, Gro99, Gru90, Gru95, Gru97, Gue90, Gun90, Gun96a, Gun99, Gun94b, Gun94a, Gun96b, Gut90, Gut92, Hab92, Had92, Hag90, Hag91, Hag96, Hal95, Hal98, Hal94, HH96, Ham96, Han90, Han93, Han97, Han98, Hap91, Hap92, Har91a, Har91b, Har91d, Har91c]. **Book** [Har92a, Has91, Haw90, Hea94, Hec90, Hec95, Hec96, Hec99, Hei90, Hem99, Hes91, Hes93, Hes97, Hey92, Hey98, Hey93, Hig98, Hil95, Hin97, Hoc94, Hof95, Hor98, Hul92, Huz95, Hwa92, IHMT95, Ing92, Iye98, Iye90, Ize90, Ize91, Jac95, Jai95, Jam96, Jan94, Jen90, Jen91, Jen92, Jen93, Job99, Joh91, Jol90, Jol93, Jol96, Jol97, Jon90, Jon91b, Jon91a, Jon92, Jon93, Kah94, Kal93, Kal98, Kan95, Kat91, KR93, KB94, Kat98, Ked96, Ked98, Kel97, Kha95, Kia90, Kia92a, Kia92b, Kia93a, Kia93b, Kia94, Kia95a, Kia95b, Kim91, Kin91, Kin93, Kin97, Kir92, Kir93, Kle94, Ko95b, Ko95a, Koe92, Koh90, Koh94, Koo90, KY91, Kot92, Kra90, Kra92, Kus92, Kus98, Kus93, LaL92, LaL95, Lal99, Lam90, Lar95, Law95, Law92, Law98]. **Book** [Law96, LC94, LC98, LeP90a, LeP90b, Lee90, Lee93, Lee94, Lee99, Lei91, Lei92, Lei93, Lei97, Lei99, Len90, Len93, Len95, Lew92, Lew93, LH97, Lin99, Lin92, Lin90, Lit91, Liu92a, Liu92b, Liu99, Loh92, Loh94, Lor92, Lor93, Lor99, LuV90, Lyn94, Lyn95, Lyn97a, Lyn97b, Lyn99, Mac90a, Mad96, Mad98, Mag90, Mag96, Mar97, Mar94, MA92, Mar99, Mas99, Mat96, Mat97, Mat98, Maz93, Maz98, McA90, McC90, McC91, McC98, McC94, McC99, McG94, McL95, Mee91a, Mee91b, Men91, Mi97, Mi99, Mil91, Mil94, Mil99, Mil90, Mil98, Min93, Moo91, Moo96, Moo99, Mor93a, Mor99a, Mor92, Mor99b, Mor97a, Mor93b, Mul97, Mye91, Mye96, Nai94, Nai96, Nan94, Nar93, Nay98, Nel98, Nem92, Nem95, Nem97, Neu99, Nik93, Nik95, Nip92, Not92a, Not92c, Not92b, O'D97, O'D99]. **Book** [Oli97, Oli98, Ord96, Osb97, Ott90, Owe91, Owe96, Pan92, Pan96, Pap95, Pap96, Par92, Pat91, Ped98, Per92, Per98, Per97, Pet99, Pfa92, Pfa99, Pie90b, Pie90a, Pig91, Pit92, Pit96, Pla90, Pla96, Pol93, Por93, Por97b, Por97a, Pos98, Pot93, Pri93, Pri98, Pro90, Pro92b, Pro92a, Pro93a, Pro93b, Pro94, Pro96, Qiu95, Rab92, Rag91, Rag93, Rag95, Ram99, Ram93, Ram91, Ram94, Ram96, Rao98, Ray93, Raz91, Rea93, Rie94b, Rie94a, Rie97, Rig92b, Rig92a, Rig93, Rig99, Rob90, Roh91, Rol93, Roz93, Ruk97a, Ruk97b, Ruk98, Run90, Rus94, Rut93, Sac93, Sai96, Sam90, Sam99b, Sam99a, San98, San92, San99, Sar90, Sar93, Sar94b, Sar94a, Sau92, Sau94, Sau97, Sau98, Sch91a, Sch92a, Sch96a, Sch91b, Sch95, Sch92c, Sch93a, Sch94a]. **Book** [Sch96b, Sch92d, Sch93c, Sch93b, Sch94b, Sch96c, Sco90, Sco91, Sco92, Sea90, Sea91, Sea93, Sea94, Sen99a, Sen94b, Sen94a, Sen95, Sen97, Sha92, Sha93, Sha95, Sha97c, Sha97b, Sha97a, Sha98, She90a, She90b, Sho90, Sim97, Sim91, Sin90a, Sin90b, Sin97, Sin98, Smi91, Smi93, Soy95, Spa99, SN95, Spe96a, Spe91, Spo90, Spr91, Sri92, Sri93, St.94, Ste90a, Ste91, Ste90c, Ste98, SG99, Ste99, Sti97, Sto96, Sto92, Str96, Stu94, Sys99, Taa91, Taa99, Tam96, Tan98, Tan93, Ter92, Thi91, Tho99, Tho90a, Tho93, Tho90b, Tho92b, Tim95, Tim96, Tim99, Tob99, Tom95, Tor95, Tor99, Tro97, Tsa91, Tso92, Van92a, Van91, Van96b, Ver90, Vin92, Voe94, Vuk98, Wad99, Wal92a, Wal92b, Wan94, War90, Was91, Was97, Wat90, Wat96]. **Book** [Web90, Weh91, Weh93, Weh95, Wei90, Wei94, Wel90, Wel93, Wen93, Wen94, Wes92, Wha95, Whe93, Wil90a, Wil90b, Wil98, Win90, Win93, Wit94, Wol91, Wol96, Wol92, Won94, Won98, Woo91, Woo92, Woz91, Wu99, Wyc96, Yak97, Yan96, Yan97, Yeh93, Yin91, Zei94, Zel94, Zha92, Zie90l, Zie90p, Zie90-28, Zie90x, Zie90-27, Zie90i, Zie90m, Zie90o, Zie90v, Zie90h, Zie90q, Zie90j, Zie90z, Zie90e, Zie90y, Zie90s, Zie90d, Zie90f, Zie90n, Zie90t, Zie90r, Zie90w, Zie90u, Zie90b, Zie90c, Zie90a, Zie90k, Zie90g, Zie91g, Zie91n, Zie91i, Zie91m, Zie91q, Zie91r, Zie91p, Zie91l, Zie91k, Zie91f, Zie91e, Zie91a, Zie91c, Zie91j, Zie91d, Zie91b, Zie91h, Zie91o, Zie92b, Zie92j, Zie92f, Zie92a, Zie92t, Zie92h, Zie92g, Zie92d, Zie92q, Zie92k, Zie92e, Zie92c, Zie92x, Zie92i]. **Book** [Zie92r, Zie92w, Zie92v, Zie92p, Zie92m, Zie92l, Zie92n, Zie92o, Zie92u, Zie92s, Zie93-30, Zie93e, Zie93c, Zie93j, Zie93t, Zie93b, Zie93-28, Zie93-31, Zie93o, Zie93w, Zie93l, Zie93-37, Zie93p, Zie93v, Zie93h, Zie93d, Zie93x, Zie93-33, Zie93r, Zie93-29, Zie93m, Zie93z, Zie93-27, Zie93-38, Zie93a, Zie93u, Zie93q, Zie93k, Zie93g, Zie93f, Zie93i, Zie93s, Zie93-32, Zie93-36, Zie93n, Zie93-34, Zie93-35, Zie93y, Zie94o, Zie94u, Zie94e, Zie94h, Zie94f, Zie94k, Zie94-42, Zie94d, Zie94w, Zie94r, Zie94t, Zie94x, Zie94-28, Zie94-29, Zie94j, Zie94a, Zie94v, Zie94-30, Zie94-41, Zie94-39, Zie94y, Zie94-31, Zie94-45, Zie94g, Zie94l, Zie94-44, Zie94b, Zie94s, Zie94-32, Zie94-40, Zie94-38, Zie94-43, Zie94-33, Zie94-36, Zie94-37, Zie94-27, Zie94z, Zie94i, Zie94p, Zie94c, Zie94m, Zie94n, Zie94-34, Zie94q, Zie94-35, Zie95q]. **Book** [Zie95-48, Zie95p, Zie95-30, Zie95u, Zie95r, Zie95-33, Zie95g, Zie95-42, Zie95-29, Zie95d, Zie95-41, Zie95i, Zie95t, Zie95-35, Zie95-45, Zie95-31, Zie95o, Zie95-38, Zie95e, Zie95-49, Zie95-32, Zie95b, Zie95h, Zie95-40, Zie95z, Zie95s, Zie95y, Zie95v, Zie95f, Zie95l, Zie95n, Zie95j, Zie95x, Zie95w, Zie95-37, Zie95-47, Zie95-46, Zie95-28, Zie95-50, Zie95m, Zie95-39, Zie95-36, Zie95-27, Zie95-34, Zie95k, Zie95c, Zie95a, Zie95-44, Zie95-43, Zie96m, Zie96-47, Zie96-34, Zie96-32, Zie96o, Zie96q, Zie96b, Zie96-28, Zie96t, Zie96d, Zie96-45, Zie96w, Zie96-30, Zie96n, Zie96-37, Zie96-41, Zie96e, Zie96-31, Zie96-44, Zie96-50, Zie96j, Zie96-43, Zie96i, Zie96h, Zie96-40, Zie96-27, Zie96a, Zie96x, Zie96-33, Zie96-35, Zie96k, Zie96-51, Zie96-52, Zie96g, Zie96-48, Zie96-29, Zie96-39, Zie96-42, Zie96p, Zie96-38, Zie96r, Zie96s, Zie96c, Zie96u, Zie96l]. **Book** [Zie96-46, Zie96f, Zie96z, Zie96-49, Zie96-36, Zie96v, Zie96y, Zie97-39,

Por97a, Pos98, Pot93, Pri93, Pri98, Pro90, Pro92b, Pro93a, Pro93b, Pro94, Pro96, Qiu95, Rab92, Rag91, Rag93, Rag95, Ram99, Ram93, Ram91, Ram94, Ram96, Rao98, Ray93, Raz91, Rea93, Rie94b, Rie94a, Rie97, Rig92b, Rig92a, Rig93, Rig99, Rob90, Roh91, Rol93, Roz93, Ruk97a, Ruk97b, Ruk98, Run90, Rus94, Rut93, Sac93, Sai96, Sam90, Sam99b, Sam99a, San98, San92, San99, Sar90, Sar93, Sar94b, Sar94a, Sau92, Sau94, Sau97, Sau98, Sch91a, Sch92a, Sch96a, Sch91b, Sch95, Sch92c, Sch93a, Sch94a, Sch96b]. **Review** [Sch92d, Sch93c, Sch93b, Sch94b, Sch96c, Sco90, Sco91, Sco92, Sea90, Sea91, Sea93, Sea94, Sen99a, Sen94b, Sen94a, Sen95, Sen97, Sha92, Sha93, Sha95, Sha97c, Sha97b, Sha97a, Sha98, She90a, She90b, Sho90, Sim97, Sim91, Sin90a, Sin90b, Sin97, Sin98, Smi91, Smi93, Soy95, Spa99, SN95, Spe96a, Spe91, Spo90, Spr91, Sri92, Sri93, St.94, Ste90a, Ste91, Ste90c, Ste98, SG99, Ste99, Sti97, Sto96, Sto92, Str96, Stu94, Sys99, Taa91, Taa99, Tam96, Tan98, Tan93, Ter92, Thi91, Tho99, Tho90a, Tho93, Tho90b, Tho92b, Tim95, Tim96, Tim99, Tob99, Tom95, Tor95, Tor99, Tro97, Tsa91, Tso92, Van92a, Van91, Van96b, Ver90, Vin92, Voe94, Vuk98, Wad99, Wal92a, Wal92b, Wan94, War90, Was91, Was97, Wat90, Wat96, Web90]. **Review** [Weh91, Weh93, Weh95, Wei90, Wei94, Wel90, Wel93, Wen93, Wen94, Wes92, Wha95, Whe93, Wil90a, Wil90b, Wil98, Win90, Win93, Wit94, Wol91, Wol96, Wol92, Won94, Won98, Woo91, Woo92, Woz91, Wu99, Wyc96, Yak97, Yan96, Yan97, Yeh93, Yin91, Zei94, Zel94, Zha92, Zie90l, Zie90p, Zie90x, Zie90i, Zie90m, Zie90o, Zie90v, Zie90h, Zie90q, Zie90j, Zie90z, Zie90e, Zie90y, Zie90s, Zie90d, Zie90f, Zie90n, Zie90t, Zie90r, Zie90w, Zie90u, Zie90b, Zie90c, Zie90a, Zie90k, Zie90g, Zie91g, Zie91n, Zie91i, Zie91m, Zie91p, Zie91l, Zie91k, Zie91f, Zie91e, Zie91a, Zie91c, Zie91j, Zie91d, Zie91b, Zie91h, Zie91o, Zie92b, Zie92j, Zie92f, Zie92a, Zie92t, Zie92h, Zie92g, Zie92d, Zie92q, Zie92k, Zie92e, Zie92c, Zie92x, Zie92i, Zie92r, Zie92w, Zie92v, Zie92p, Zie92m]. **Review** [Zie92l, Zie92n, Zie92o, Zie92u, Zie92s, Zie93-30, Zie93e, Zie93c, Zie93j, Zie93t, Zie93b, Zie93-28, Zie93-31, Zie93o, Zie93w, Zie93l, Zie93-37, Zie93p, Zie93v, Zie93h, Zie93d, Zie93x, Zie93-33, Zie93r, Zie93-29, Zie93m, Zie93z, Zie93-27, Zie93-38, Zie93a, Zie93u, Zie93q, Zie93k, Zie93g, Zie93f, Zie93i, Zie93s, Zie93-32, Zie93-36, Zie93n, Zie93-34, Zie93-35, Zie93y, Zie94o, Zie94u, Zie94e, Zie94h, Zie94f, Zie94k, Zie94-42, Zie94d, Zie94w, Zie94r, Zie94t, Zie94x, Zie94-28, Zie94-29, Zie94j, Zie94a, Zie94v, Zie94-30, Zie94-41, Zie94-39, Zie94y, Zie94-31, Zie94g, Zie94l, Zie94-44, Zie94b, Zie94s, Zie94-32, Zie94-40, Zie94-38, Zie94-43, Zie94-33, Zie94-36, Zie94-37, Zie94-27, Zie94z, Zie94i, Zie94p, Zie94c, Zie94m, Zie94n, Zie94-34, Zie94q, Zie94-35, Zie95q, Zie95-48, Zie95p, Zie95-30, Zie95u, Zie95r, Zie95-33]. **Review** [Zie95g, Zie95-42, Zie95-29, Zie95d, Zie95-41, Zie95i, Zie95t, Zie95-35, Zie95-45, Zie95-31, Zie95o, Zie95-38, Zie95e, Zie95-32, Zie95b, Zie95h, Zie95-40, Zie95z, Zie95s, Zie95y, Zie95v, Zie95f, Zie95l, Zie95n, Zie95j, Zie95x, Zie95w, Zie95-37, Zie95-47, Zie95-46, Zie95-28, Zie95m, Zie95-39, Zie95-36, Zie95-27, Zie95-34, Zie95k, Zie95c, Zie95a, Zie95-44, Zie95-43, Zie96m, Zie96-47, Zie96-34, Zie96-32, Zie96o, Zie96q, Zie96b, Zie96-28, Zie96t, Zie96d,

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